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09/626 06 PRO
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	Subclass
	Class
ISSUE CLASSIFICATION	

PATENT NUMBER

U.S. UTILITY Patent Application

(2768) O.I.P.E.		PATENT DATE
SCANNED	<i>A.A.</i>	Q.A. CS 2

APPLICATION NO. 09/626106	CONT/PRIOR F	CLASS 250	SUBCLASS 306	ART UNIT 2881	EXAMINER <i>S. O. W.</i>
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APPLICANTS
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TITLE
Scanning Probe microscope and method of measurement

PTO-2040
12/99

ISSUING CLASSIFICATION					
ORIGINAL		CROSS REFERENCE(S)			
CLASS	SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)		
INTERNATIONAL CLASSIFICATION					
<input type="checkbox"/> Continued on Issue Slip Inside File Jacket					

TERMINAL DISCLAIMER	DRAWINGS			CLAIMS ALLOWED	
	Sheets Drwg.	Figs. Drwg.	Print Fig.	Total Claims	Print Claim for O.G.
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<input type="checkbox"/> The term of this patent shall not extend beyond the expiration date of U.S Patent. No. _____ _____				ISSUE FEE	
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